MOTOROLA SEMICONDUCTOR TECHNICAL DATA

Designer's Data Sheet

Power Field Effect Transistor

P-Channel Enhancement-Mode Silicon Gate

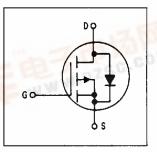
This TMOS Power FET is designed for medium voltage, high speed power switching applications such as switching regulators, converters, solenoid and relay drivers.

- Silicon Gate for Fast Switching Speeds Switching Times Specified at 100°C
- Designer's Data IDSS, VDS(on), VGS(th) and SOA Specified at Elevated Temperature
- Rugged SOA is Power Dissipation Limited
- Source-to-Drain Diode Characterized for Use With Inductive Loads





TMOS POWER FET
7 AMPERES
RDS(on) = 0.6 OHM
60 VOLTS



MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain-Source Voltae	VDSS	60	Vdc
Drain-Gate Voltage (RGS = 1 MΩ)	VDGR	60	Vdc
Gate-Source Voltage — Continuous — Non-repetitive (t _p ≤ 50 μs)	V _{GS} V _{GSM}	± 20 ± 40	Vdc Vpk
Drain Current Continuous Pulsed	I _D	7 21	Adc
Total Power Dissipation @ T _C = 25°C Derate above 25°C	PD	75 0.6	Watts W/°C
Operating and Storage Temperature Range	T _J , T _{stg}	-65 to 150	°C

THERMAL CHARACTERISTICS

Thermal Resistance				°C/W
Junction to Case		R _{ØJC}	1.67	
Junction to Ambient	TO-220	R _{OJA}	62.5	
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 5 seconds		TL	260	°C



Designer's Data for "Worst Case" Conditions — The Designer's Data Sheet permits the design of most circuits entirely from the information presented. SOA Limit curves — representing boundaries on device characteristics — are given to facilitate "worst case" design.



MTP7P06

Charac	teristic	Symbol	Min	Мах	Unit
FF CHARACTERISTICS	=				
Drain-Source Breakdown Voltage (VGS = 0, ID = 0.25 mA)		V _{(BR)DSS}	60	_	Vdc
Zero Gate Voltage Drain Current (VDS = Rated VDSS, VGS = 0) (VDS = Rated VDSS, VGS = 0, TJ = 125°C)		IDSS		10 100	μAdc
Gate-Body Leakage Current, Forward (VGSF = 20 Vdc, VDS = 0)		IGSSF	_	100	nAdc
Gate-Body Leakage Current, Reverse (VGSR = 20 Vdc, VDS = 0)		IGSSR	_	100	nAdc
N CHARACTERISTICS*					
Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_{D} = 1$ mA) $T_{J} = 100^{\circ}C$		V _{GS(th)}	2 1.5	4.5 4	Vdc
Static Drain-Source On-Resistance (VGS = 10 Vdc, ID = 3.5 Adc)		R _{DS(on)}	-	0.6	Ohm
Drain-Source On-Voltage ($V_{GS} = 10$ ($I_D = 7$ Adc) ($I_D = 3.5$ Adc, $T_J = 100^{\circ}$ C)	V)	V _{DS{on}}	_	4.2 4	Vdc
Forward Transconductance (V _{DS} = '	15 V, I _D = 3.5 A)	9FS	1.5	_	mhos
YNAMIC CHARACTERISTICS					
Input Capacitance	$(V_{DS} = 25 \text{ V}, V_{GS} = 0,$	Ciss	_	700	ρF
Output Capacitance	f = 1 MHz) See Figure 11	Coss	_	400	
Reverse Transfer Capacitance		Crss	_	150	
WITCHING CHARACTERISTICS* (TJ =	= 100°C)				
Turn-On Delay Time		td(on)	_	40	пѕ
Rise Time	(V _{DD} = 25 V, I _D = 0.5 Rated I _D R _{gen} = 50 ohms) See Figures 9, 13 and 14	t _r	_	120	
Turn-Off Delay Time		td(off)	_	80	
Fall Time		tf	_	70	
Total Gate Charge	$(V_{DS} = 0.8 \text{ Rated } V_{DSS},$	Qg	12 (Typ)	16	nC
Gate-Source Charge	ID = Rated ID, VGS = 10 V) See Figure 12	Ogs	7 (Typ)		
Gate-Drain Charge		a_{gd}	5 (Typ)		
OURCE DRAIN DIODE CHARACTERIS	TICS*				
Forward On-Voltage	(IS = Rated ID	V _{SD}	1.8 (Typ)	2.5	Vdc
Forward Turn-On Time	$V_{GS} = 0$	ton	Limited	by stray ind	luctance
Reverse Recovery Time		t _{rr}	325 (Typ)	_	ns
NTERNAL PACKAGE INDUCTANCE (T	0-220)				
Internal Drain Inductance (Measured from contact screw on tab to center of die) (Measured from the drain lead 0.25" from package to center of die)		L _d	3.5 (Typ) 4.5 (Typ)	_	nH
Internal Source Inductance (Measured from the source lead 0.25" from package to center of pad)		L _S	7.5 (Typ)		

^{*}Pulse Test* Pulse Width \leqslant 300 $\mu \rm{s}$, Duty Cycle \leqslant 2%.

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TYPICAL ELECTRICAL CHARACTERISTICS

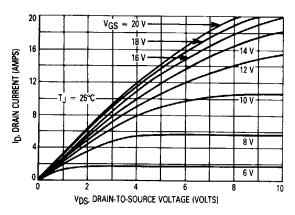


Figure 1. On-Region Characteristics

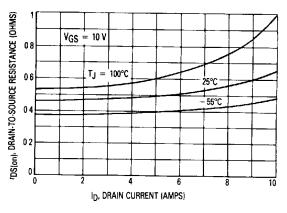


Figure 2. Gate-Threshold Voltage Variation With Temperature

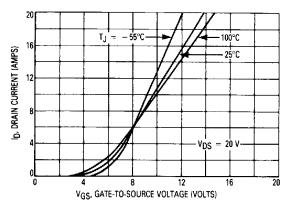


Figure 3. Transfer Characteristics

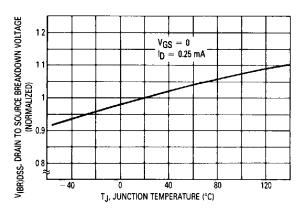


Figure 4. Breakdown Voltage Variation With Temperature

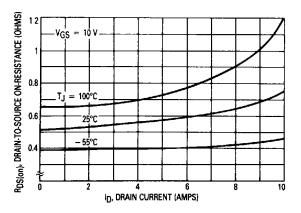


Figure 5. On-Resistance versus Drain Current

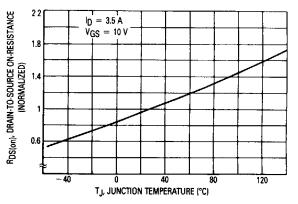


Figure 6. On-Resistance Variation With Temperature

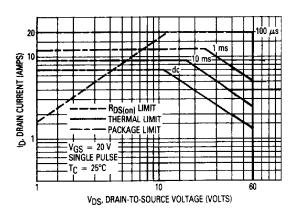


Figure 7. Maximum Rated Forward Biased Safe Operating Area

FORWARD BIASED SAFE OPERATING AREA

The FBSOA curves define the maximum drain-tosource voltage and drain current that a device can safely handle when it is forward biased, or when it is on, or being turned on. Because these curves include the limitations of simultaneous high voltage and high current, up to the rating of the device, they are especially useful to designers of linear systems. The curves are based on a case temperature of 25°C and a maximum junction temperature of 150°C. Limitations for repetitive pulses at various case temperatures can be determined by using the thermal response curves. Motorola Application Note, AN569, "Transient Thermal Resistance-General Data and Its Use" provides detailed instructions.

SWITCHING SAFE OPERATING AREA

The switching safe operating area (SOA) of Figure 8 is the boundary that the load line may traverse without incurring damage to the MOSFET. The fundamental limits are the peak current, IDM and the breakdown voltage, V(BR)DSS. The switching SOA shown in Figure 8 is applicable for both turn-on and turn-off of the devices for switching times less than one microsecond.

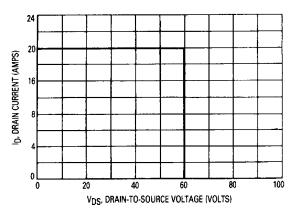


Figure 8. Maximum Rated Switching Safe Operating Area

The power averaged over a complete switching cycle must be less than:

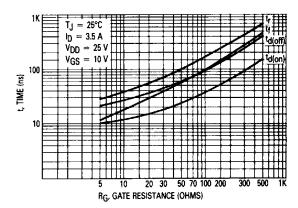


Figure 9. Resistive Switching Time Variation versus Gate Resistance

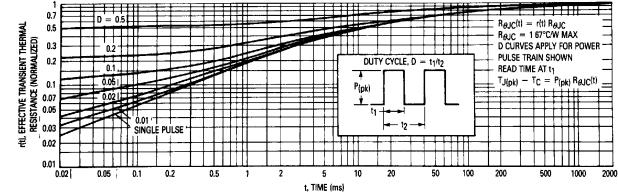
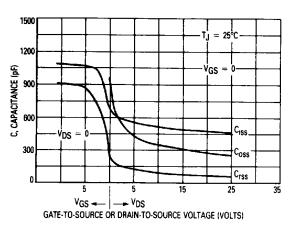


Figure 10. Thermal Response

TYPICAL CHARACTERISTICS



| T_J = 25°C | T_D = 7 A | T

Figure 12. Capacitance Variation

Figure 13. Gate Charge versus Gate-To-Source Voltage

RESISTIVE SWITCHING

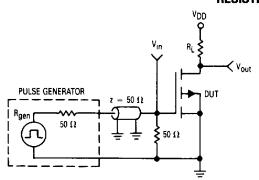


Figure 14. Switching Test Circuit

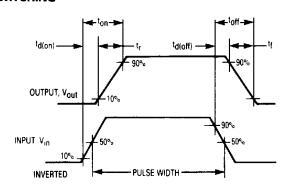


Figure 15. Switching Waveforms